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Application/Control No.	Applicant(s)/Pate Reexamination	ent under
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SEARCHED			
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NA	NA	5/8/2007	BS
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SEARCH NOT (INCLUDING SEARCH)
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STN-see printout.	5/8/2007	BS
Priority document checked.	5/8/2007	BS
Inventor name searched.	5/8/2007	BS
SEQ search NA.	5/8/2007	BS